

10583660 CLSTITLES

Titles of most frequently occurring classifications of patents returned from a search of 10583660 on Apr 20, 2009

- 4 430/5 (4 OR, 0 XR)
Class 430 RADIATION IMAGERY CHEMISTRY: PROCESS, COMPOSITION, OR
PRODUCT THEREOF
430/4 .. RADIATION MODIFYING PRODUCT OR PROCESS OF MAKING
430/5 .. Radiation mask
- 4 250/492.2 (1 OR, 3 XR)
Class 250 RADIANT ENERGY
250/492.1 .. IRRADIATION OF OBJECTS OR MATERIAL
250/492.2 .. Irradiation of semiconductor devices
- 4 382/141 (3 OR, 1 XR)
Class 382 IMAGE ANALYSIS
382/100 .. APPLICATIONS
382/141 .. Manufacturing or product inspection
- 3 250/491.1 (2 OR, 1 XR)
Class 250 RADIANT ENERGY
250/491.1 .. MEANS TO ALIGN OR POSITION AN OBJECT RELATIVE TO A SOURCE
OR DETECTOR
- 3 356/71 (2 OR, 1 XR)
Class 356 OPTICS: MEASURING AND TESTING
356/71 .. DOCUMENT PATTERN ANALYSIS OR VERIFICATION
- 2 382/147 (1 OR, 1 XR)
Class 382 IMAGE ANALYSIS
382/100 .. APPLICATIONS
382/141 .. Manufacturing or product inspection
382/145 ... Inspection of semiconductor device or printed circuit
board
382/147 Inspecting printed circuit boards
- 2 382/149 (1 OR, 1 XR)
Class 382 IMAGE ANALYSIS
382/100 .. APPLICATIONS
382/141 .. Manufacturing or product inspection
382/145 ... Inspection of semiconductor device or printed circuit
board
382/149 Fault or defect detection
- 2 348/126 (0 OR, 2 XR)
Class 348 TELEVISION
348/61 .. SPECIAL APPLICATIONS
348/125 .. Flaw detector
348/126 ... Of electronic circuit chip or board
- 2 250/310 (1 OR, 1 XR)
Class 250 RADIANT ENERGY
250/306 .. INSPECTION OF SOLIDS OR LIQUIDS BY CHARGED PARTICLES
250/310 .. Electron probe type
- 2 250/307 (1 OR, 1 XR)
Class 250 RADIANT ENERGY
250/306 .. INSPECTION OF SOLIDS OR LIQUIDS BY CHARGED PARTICLES
250/307 .. Methods
- 2 430/322 (0 OR, 2 XR)
Class 430 RADIATION IMAGERY CHEMISTRY: PROCESS, COMPOSITION, OR

PRODUCT THEREOF

430/269 . . IMAGING AFFECTING PHYSICAL PROPERTY OF RADIATION SENSITIVE
 MATERIAL, OR PRODUCING NONPLANAR OR PRINTING SURFACE - PROCESS, COMPOSITION, OR
 PRODUCT

430/322 . . Forming nonplanar surface

2 714/720 (2 OR, 0 XR)

Class 714 ERROR DETECTION/ CORRECTION AND FAULT DETECTION/ RECOVERY
 714/699 . PULSE OR DATA ERROR HANDLING
 714/718 . . Memory testing
 714/719 . . . Read-in with read-out and compare
 714/720 . . . Special test pattern (e.g., checkerboard, walking ones)

2 365/200 (0 OR, 2 XR)

Class 365 STATIC INFORMATION STORAGE AND RETRIEVAL
 365/189.011 . READ/ WRITE CIRCUIT
 365/200 . . Bad bit

2 714/766 (0 OR, 2 XR)

Class 714 ERROR DETECTION/ CORRECTION AND FAULT DETECTION/ RECOVERY
 714/699 . PULSE OR DATA ERROR HANDLING
 714/746 . . Digital data error correction
 714/752 . . . Forward correction by block code
 714/763 . . . Memory access
 714/766 Check bits stored in separate area of memory

2 714/E11.036 (0 OR, 2 XR)

Class 714 ERROR DETECTION/ CORRECTION AND FAULT DETECTION/ RECOVERY
 714/E11.001 . ERROR DETECTION; ERROR CORRECTION; MONITORING (EPO)
 714/E11.021 . . Responding to the occurrence of a fault, e.g., fault
 tolerance, etc. (EPO)
 714/E11.03 . . . Error detection or correction by redundancy in data
 representation, e.g., by using checking codes, etc. (EPO)
 714/E11.032 . . . Adding special bits or symbols to the coded information,
 e.g., parity check, casting out 9's or 11's, etc. (EPO)
 714/E11.034 In memories (EPO)
 714/E11.035 In static stores (EPO)
 714/E11.036 Integrated on a chip (EPO)

2 714/805 (0 OR, 2 XR)

Class 714 ERROR DETECTION/ CORRECTION AND FAULT DETECTION/ RECOVERY
 714/699 . PULSE OR DATA ERROR HANDLING
 714/799 . . Error/fault detection technique
 714/800 . . . Parity bit
 714/805 . . . Storage accessing (e.g., address parity check)

2 365/201 (0 OR, 2 XR)

Class 365 STATIC INFORMATION STORAGE AND RETRIEVAL
 365/189.011 . READ/ WRITE CIRCUIT
 365/201 . . Testing